

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/633,157	PARK ET AL.	
Examiner	Art Unit	
Xavier Szewai Wong	2616	

	SEARCHED					
Class	Subclass	Date	Examiner			
updated	search					
370	445-448	2/4/2008	XSW			
370	445-448	3/1/2008	XSW			
370	445-448	3/12/2008	XSW			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
370	445-448	3/12/2008	xsw		
	229,338	3/12/2008	XSW		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
updated EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	2/4/2008	XSW
updated EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	3/1/2008	XSW
updated EAST image and keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO, and IBM_TDB (please see search history)	3/12/2008	XSW
consulted with Seema Rao	3/1/2008	XSW
updated NPL (IEEE) search	3/12/2008	XSW

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